(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property Organization
International Bureau

(43) International Publication Date
14 August 2003 (14.08.2003)

PCT

(10) International Publication Number
WO 03/067650 A1

(51) International Patent Classification[7]: H01L 21/66

(21) International Application Number: PCT/KR02/02073

(22) International Filing Date:
8 November 2002 (08.11.2002)

(25) Filing Language: Korean

(26) Publication Language: English

(30) Priority Data:
2002-6367 5 February 2002 (05.02.2002) KR
10-2002-0068402
6 November 2002 (06.11.2002) KR

(71) Applicant: PHICOM CORPORATION [KR/KR]; 60-29, Gasan-dong, Kumchon-gu, 153-801 Seoul (KR).

(71) Applicant and
(72) Inventor: Lee, Oug-Ki [KR/KR]; A/12, Green Villa, 1-5, Hang-dong, Guro-gu, 152-140 Seoul (KR).

(74) Agent: KIM, In-Han; 6F., Kyungmin Bldg. 18-3, Jamwon-dong, Seocho-gu, Seoul 137-903 (KR).

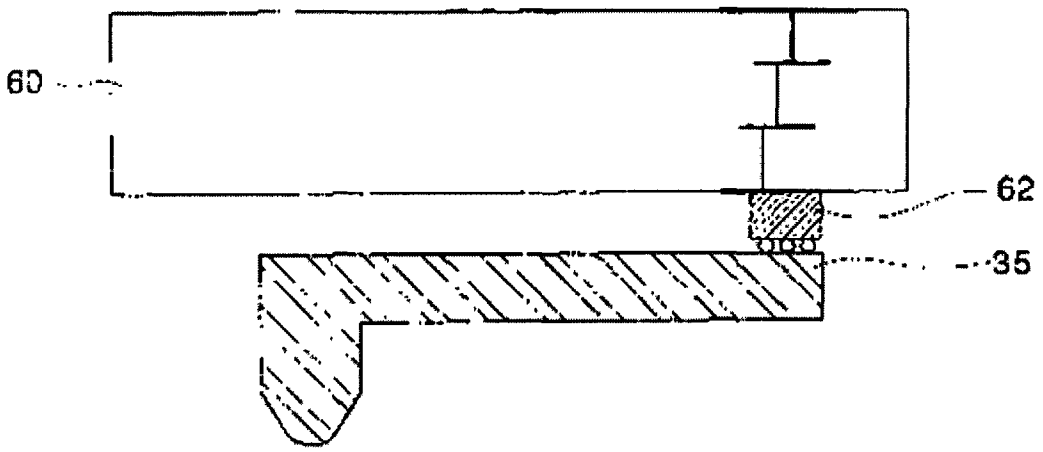
(81) Designated States *(national)*: AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NO, NZ, OM, PH, PL, PT, RO, RU, SC, SD, SE, SG, SI, SK, SL, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW.

(84) Designated States *(regional)*: ARIPO patent (GH, GM, KE, LS, MW, MZ, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Published:
— *with international search report*

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

(54) Title: METHOD FOR MANUFACTURING ELECTRIC CONTACT ELEMENT FOR TESTING ELECTRO DEVICE AND ELECTRIC CONTACT ELEMENT THEREBY



(57) Abstract: Disclosed is a method for manufacturing an electrical contact element used to test an electronic device, and an electrical contact element manufactured with forming the electrical contact element having the tip portion and the beam portion. The method comprises the step of conducting one or more times, after defining the trench, anisotropic etching in the trench in such a way as to increase a depth of the trench and round an inner surface of the trench. The electrical contact element comprises a beam portion having a multi-stepped configuration which comprises a three, bar-shaped part with having a width greater than the upper part. Each parts are connected at the other end thereof with an electronic component, through a bump; and a tip portion formed integrally with a free end of the first part of the beam portion.

WO 03/067650 A1